

Application/Control No.	Applicant(s)/Patent under Reexamination
10/588,401	BIRZER ET AL.
Examiner	Art Unit
CHRIS C. CHU	2815

SEARCHED					
OLANOILE I					
Class	Subclass	Date	Examiner		
257	E27.137, E27.144 & E27.161	12/3/2008	C.C.		
257	723 & 724	12/3/2008	C.C.		
257	685 & 686	12/3/2008	C.C.		
257	777	12/3/2008	C.C.		
438	108 & 109	12/3/2008	C.C.		
361	760	12/3/2008	C.C.		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
As same	as above	12/3/2008	C.C.		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	12/3/2008	C.C.